

Application/Control No.	Applicant(s)/Patent under Reexamination TOMIKAWA ET AL.	
10/790,800		
Examiner	Art Unit	
John S. Chu	1752	

SEARCHED					
Class	Subclass	Date	Examiner		
403	18	6/2016	Jee-		
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430	326)		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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